TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOSIII)

TPCS8208

Lithium Ion Battery Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance: RDS (ON) = 13 m Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 15 S$ (typ.)
- Low leakage current: IDSS = 10 μA (max) (VDS = 20 V)
- Enhancement mode: $V_{th} = 0.5 \sim 1.2 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 200 \mu\text{A})$
- Common drain

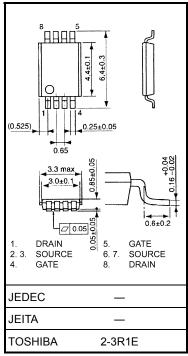
Maximum Ratings (Ta = 25°C)

Char	acteristics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	20	V	
Drain-gate voltag	ge (R _{GS} = 20 kΩ)	V_{DGR}	20	V	
Gate-source volt	age	V _{GSS}	±12	٧	
Drain current	DC (Note 1)	I _D	6	Α	
Diam current	Pulse (Note 1)	I_{DP}	24	^	
Drain power	Single-device operation (Note 3a)	P _{D (1)}	1.1		
dissipation (t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.75	W	
Drain power	Single-device operation (Note 3a)	P _{D (1)}	0.6	W	
dissipation (t = 10 s) (Note 2b)	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.35		
Single pulse ava	Single pulse avalanche energy (Note 4)		46.8	mJ	
Avalanche currei	Avalanche current		6	Α	
Repetitive avalanche energy Single-device value at dual operation (Note 2a, 3b, 5)		E _{AR}	0.075	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	−55~150	°C	

Note 1, Note 2, Note 3, Note 4, Note 5: See the next page.

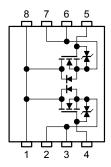
This transistor is an electrostatic-sensitive device. Please handle with caution.

Unit: mm



Weight: 0.035 g (typ.)

Circuit Configuration

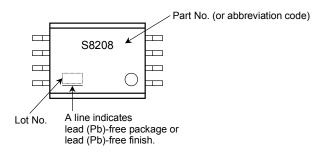




Thermal Characteristics

Characteristics	Symbol	Max	Unit		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	114	°C/W	
(t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	167		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	208		
(t = 10 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	357	°C/W	

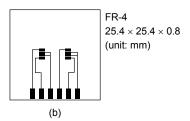
Marking (Note 6)



Note 1: Ensure that the channel temperature does not exceed 150°C.

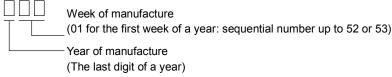
Note 2:

- a) Device mounted on a glass-epoxy board (a)
 - FR-4 25.4 × 25.4 × 0.8 (unit: mm)
- b) Device mounted on a glass-epoxy board (b)



Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.)
- Note 4: $V_{DD}=16~V,~T_{Ch}=25^{\circ}C$ (initial), $L=1.0~mH,~R_{G}=25~\Omega,~I_{AR}=6~A$
- Note 5: Repetitive rating: pulse width limited by maximum channel temperature
- Note 6: on lower right of the marking indicates Pin 1.
 - Weekly code: (Three digits)



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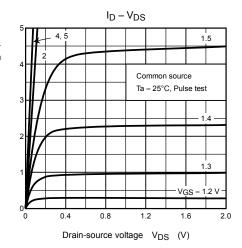
Electrical Characteristics (Ta = 25°C)

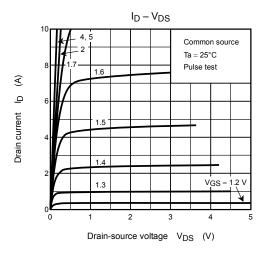
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	rrent	I _{GSS}	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Drain cut-OFF cu	urrent	I _{DSS}	V _{DS} = 20 V, V _{GS} = 0 V	_	_ 10		μА
Drain source bre	Drain-source breakdown voltage		$I_D = 10$ mA, $V_{GS} = 0$ V	20	_	_	V
Dialii-souice bie	akuowii voitage	V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -12 \text{ V}$	8 — —		·	
Gate threshold v	oltage	V_{th}	$V_{DS}=10~V,~I_D=200~\mu A$	0.5	_	1.2	V
			$V_{GS} = 2.0 \text{ V}, I_D = 4.2 \text{ A}$	_	24	35	mΩ
Drain-source ON	resistance	R _{DS (ON)}	V _{GS} = 2.5 V, I _D = 4.2 A	_	18	22	
			V _{GS} = 4.0 V, I _D = 4.8 A		13	17	
Forward transfer	admittance	Y _{fs}	$V_{DS} = 10 \text{ V}, I_D = 3.0 \text{ A}$	7.5	15	_	S
Input capacitance		C _{iss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		2160	_	pF
Reverse transfer capacitance		C _{rss}			210	_	
Output capacitance		C _{oss}			230	_	
	Rise time	t _r	Acs 0 A 1 D = 3 V AOUT	_	5	_	- ns
Switching time	Turn-ON time	t _{on}		_	13	_	
	Fall time	t _f		_	10	_	
	Turn-OFF time	t _{off}	V _{DD} ≃ 10 V Duty ≦ 1%, t _W = 10 μs	_	53	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq 16 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 6 \text{ A}$	_	22	_	
Gate-source charge 1		Q _{gs1}		_	4	_	nC
Gate-drain ("miller") charge		Q _{gd}		_	5	_	

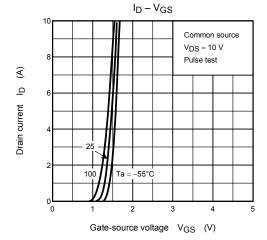
Source-Drain Ratings and Characteristics (Ta = 25°C)

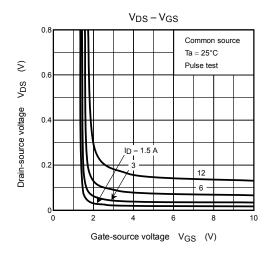
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	_	_	_	24	Α
Forward voltage (diode)		V _{DSF}	$I_{DR} = 6 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.2	V

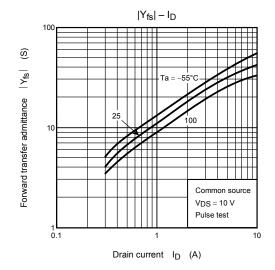
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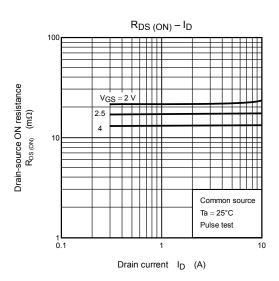


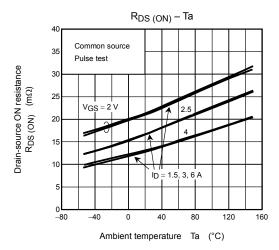


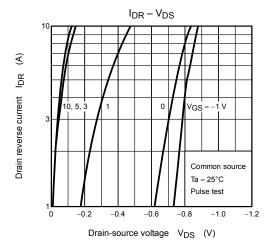


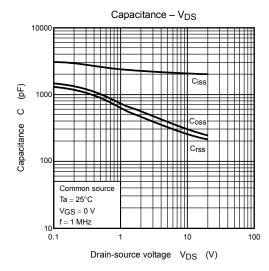


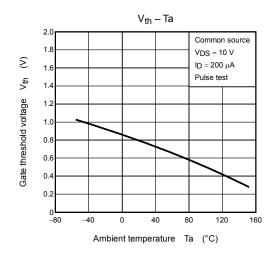


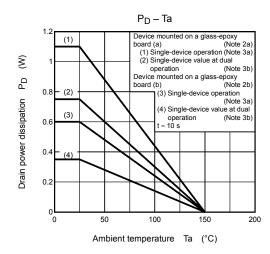


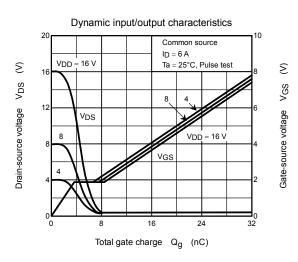


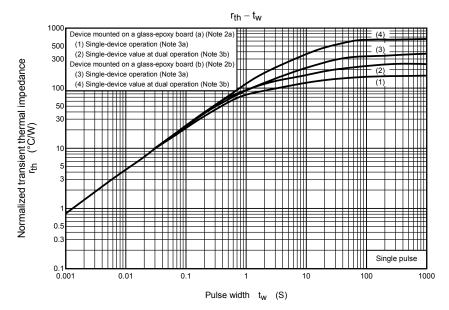




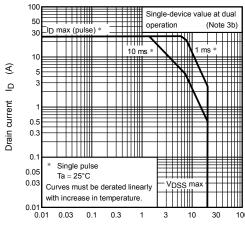








Sate operating area



Drain-source voltage $\ V_{DS}\ (V)$

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Handbook" etc..

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